







CD4051B, CD4052B, CD4053B

SCHS047L - AUGUST 1998 - REVISED SEPTEMBER 2023

CD405xB CMOS Single 8-Channel Analog Multiplexer or Demultiplexer With Logic-Level Conversion

1 Features

- Wide range of digital and analog signal levels:
 - Digital: 3 V to 20 V
 - Analog: ≤ 20 V_{P-P}
- Low ON resistance, 125 Ω (typical) over 15 V_{P-P} signal input range for $V_{DD} - V_{EE} = 18 \text{ V}$
- High OFF resistance, channel leakage of ± 100 pA (typical) at $V_{DD} - V_{EE} = 18$ V
- Logic-level conversion for digital addressing signals of 3 V to 20 V ($V_{DD} - V_{SS} = 3 V$ to 20 V) to switch analog signals to 20 V_{P-P} ($V_{DD} - V_{FF}$ = 20 V) matched switch characteristics, r_{ON} = 5 Ω (typical) for $V_{DD} - V_{EE} = 15 \text{ V very low quiescent}$ power dissipation under all digital-control input and supply conditions, 0.2 µW (typical) at $V_{DD} - V_{SS} = V_{DD} - V_{EE} = 10 \text{ V}$
- Binary address decoding on chip
- 5 V, 10 V, and 15 V parametric ratings
- 100% tested for quiescent current at 20 V
- Maximum input current of 1 µA at 18 V over full package temperature range, 100 nA at 18 V and
- Break-before-make switching eliminates channel overlap

2 Applications

- Analog and digital multiplexing and demultiplexing
- Analog to digital and digital to analog conversion
- Signal gating
- Factory automation
- **Televisions**
- **Appliances**
- Consumer audio
- Programmable logic circuits
- Sensors

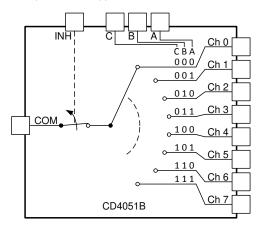
3 Description

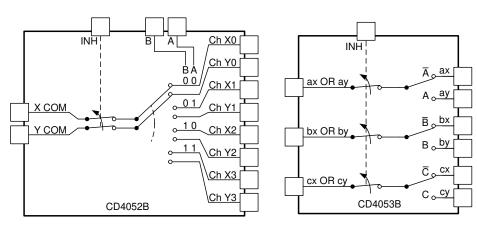
The CD405xB analog multiplexers and demultiplexers are digitally-controlled analog switches having low ON impedance and very low OFF leakage current. These multiplexer circuits dissipate extremely low quiescent power over the full $V_{DD} - V_{SS}$ and $V_{DD} - V_{EE}$ supplyvoltage ranges, independent of the logic state of the control signals.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾		
	J (CDIP, 16)	19.50 mm × 6.92 mm		
	N (PDIP, 16)	19.3 mm × 9.4 mm		
CD405xB	D (SOIC, 16)	9.9 mm × 6 mm		
	NS (SOP, 16)	10.2 mm × 7.8 mm		
	PW (TSSOP, 16)	5 mm × 6.4 mm		

- For all available packages, see the orderable addendum at the end of the data sheet.
- The package size (length × width) is a nominal value and includes pins, where applicable.





Functional Diagrams of CD405xB



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4 Revision History	may differ from page numbers in the current versi	on
Changes from Revision K (March 2023) to		
	· · · · · · · · · · · · · · · · · · ·	Page
• Changed the format of the ESD Ratings,	mation table to include package lead size Electrical Characteristics, and AC Performance to	consolidate
Changes from Revision J (February 2023)) to Revision K (March 2023)	Page
Added PW package information throughout	out the data sheet	1
Changes from Revision I (September 201	7) to Revision J (February 2023)	Page
 Updated the numbering format for tables 	, figures, and cross-references throughout the doc	ument1
	DD Max typical and maximum values	
	ent: Any Channel OFF (Max) or ALL Channels OF	
•		•
Updated the ON Channel Leakage Curre	nt: Any Channel ON (Max) or ALL Channels ON (Common OLIT/INI)
,		
	values	
 Updated the Input Current, IIN (Max) typi 	cal values	
• Updated the Inhibit-to-Signal OUT (Chan	nel Turning OFF) typical values	5
Updated the <i>Inhibit-to-Signal OUT (Chan</i>Updated the values in the <i>ESD Ratings</i> s	ection	5 5
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Added Device Information table......1



5 Pin Configuration and Functions

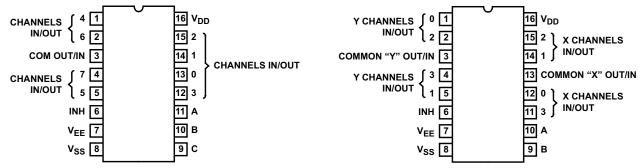


Figure 5-1. CD4051B E, M, NS, and PW Package, 16-Pin PDIP, CDIP, SOIC, SOP, and TSSOP (Top View)

Figure 5-2. CD4052B E, M, NS, and PW Package, 16-Pin PDIP, CDIP, SOP, and TSSOP (Top View)

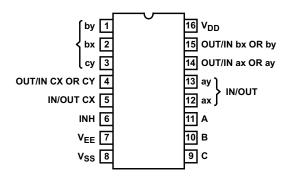


Figure 5-3. CD4053B E, M, NS, and PW Package, 16-Pin PDIP, CDIP, SOP, and TSSOP (Top View)

	PIN	TYPE(1)	DESCRIPTION
NO.	NAME	I TPE("/	DESCRIPTION
1	CH 4 IN/OUT	I/O	Channel 4 in/out
2	CH 6 IN/OUT	I/O	Channel 6 in/out
3	COM OUT/IN	I/O	Common out/in
4	CH 7 IN/OUT	I/O	Channel 7 in/out
5	CH 5 IN/OUT	I/O	Channel 5 in/out
6	INH	I	Disables all channels. See Table 8-1.
7	V _{EE}	_	Negative power input
8	V _{SS}	_	Ground
9	С	I	Channel select C. See Table 8-1.
10	В	I	Channel select B. See Table 8-1.
11	A	I	Channel select A. See Table 8-1.
12	CH 3 IN/OUT	I/O	Channel 3 in/out
13	CH 0 IN/OUT	I/O	Channel 0 in/out

Channel 1 in/out

Channel 2 in/out

Positive power input

Table 5-1. Pin Functions CD4051B

 V_{DD}

14

15

16

CH 1 IN/OUT

CH 2 IN/OUT

I/O

I/O

⁽¹⁾ I = input, O = output



Table 5-2. Pin Functions CD4052B

	PIN	TYPE ⁽¹⁾	DESCRIPTION
NO.	NAME	ITPE\''	DESCRIPTION
1	Y CH 0 IN/OUT	I/O	Channel Y0 in/out
2	Y CH 2 IN/OUT	I/O	Channel Y2 in/out
3	Y COM OUT/IN	I/O	Y common out/in
4	Y CH 3 IN/OUT	I/O	Channel Y3 in/out
5	Y CH 1 IN/OUT	I/O	Channel Y1 in/out
6	INH	I	Disables all channels. See Table 8-1.
7	V _{EE}	_	Negative power input
8	V _{SS}	_	Ground
9	В	I	Channel select B. See Table 8-1.
10	A	I	Channel select A. See Table 8-1.
11	X CH 3 IN/OUT	I/O	Channel X3 in/out
12	X CH 0 IN/OUT	I/O	Channel X0 in/out
13	X COM IN/OUT	I/O	X common out/in
14	X CH 1 IN/OUT	I/O	Channel in/out
15	X CH 2 IN/OUT	I/O	Channel in/out
16	V_{DD}	_	Positive power input

(1) I = input, O = output

Table 5-3. Pin Functions CD4053B

	PIN	TYPE ⁽¹⁾	DESCRIPTION
NO.	NAME	ITPE(*)	DESCRIPTION
1	BY IN/OUT	I/O	B channel Y in/out
2	BX IN/OUT	I/O	B channel X in/out
3	CY IN/OUT	I/O	C channel Y in/out
4	CX OR CY OUT/IN	I/O	C common out/in
5	CX IN/OUT	I/O	C channel X in/out
6	INH	1	Disables all channels. See Table 8-1.
7	V _{EE}	_	Negative power input
8	V _{SS}	_	Ground
9	С	1	Channel select C. See Table 8-1.
10	В	1	Channel select B. See Table 8-1.
11	A	1	Channel select A. See Table 8-1.
12	AX IN/OUT	I/O	A channel X in/out
13	AY IN/OUT	I/O	A channel Y in/out
14	AX OR AY OUT/IN	I/O	A common out/in
15	BX OR BY OUT/IN	I/O	B common out/in
16	V _{DD}	_	Positive power input

(1) I = input, O = output



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1) (2)

			MIN	MAX	UNIT
	Supply Voltage	V+ to V-, Voltages Referenced to V _{SS} Terminal	-0.5	20	V
	DC Input Voltage		-0.5	V _{DD} +0.5	V
	DC Input Current	Any One Input	-10	10	mA
T _{JMAX1}	Maximum junction tempera	ature, ceramic package		175	°C
T _{JMAX2}	Maximum junction tempera	ature, plastic package		150	°C
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Rating may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Condition. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
CD405xB a	ll packages			
V	Floatroatatic disabarra	Human body model (HBM), per ANSI/ESDA/ JEDEC JS-001, all pins ⁽¹⁾	±2000	V
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	±500	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

	MIN	NOM M	AΧ	UNIT
Temperature Range	– 55	1	25	°C

6.4 Thermal Information

		CD405x					
	THERMAL METRIC(1)	E (PDIP)	M (SOIC)	NS (SOP)	PW (TSSOP)	UNIT	
		16 PINS	16 PINS	16 PINS	16 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	67	73	64	116.5	°C/W	

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

⁽²⁾ All voltages are with respect to ground, unless otherwise specified.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.5 Electrical Characteristics

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5 \text{ V}$, and $R_L = 100 \Omega$, (unless otherwise noted)⁽¹⁾

PARAMETER		TE	ST CONDIT	IONS		MIN TYP	MAX	UNIT
SIGNAL INPUTS (V _{IS}) AND OUTPUTS (\	/os)							
	V _{IS} (V)	V _{EE} (V)	V _{SS} (V)	V _{DD} (V)	TEMP			
					–55°C		60	
				5 V	-40°C		60	
		0 V	0 V		25°C	17	60	
					85°C		150	
					125°C		150	
					–55°C		60	
					–40°C		60	
		0 V	0 V	10 V	25°C	18	60	
					85°C		300	
uiescent Device Current, I _{DD} Max					125°C		300	
. 25					–55°C		60	μΑ
					-40°C		60	
		0 V	0 V	0 V 15 V	25°C	18	60	
					85°C		600	
					125°C		600	
					–55°C		100	
					-40°C		100	
		0 V	0 V	20 V	25°C	18	100	
					85°C		3000	
					125°C		3000	
				5 V	–55°C		800	
					–40°C		850	
		0 V	0 V		25°C	470	1050	
					85°C		1200	
					125°C		1300	
					–55°C		310	
					–40°C		300	
Drain to Source ON Resistance r_{ON} Max $0 \le V_{IS} \le V_{DD}$		0 V	0 V	10 V	25°C	180	400	Ω
0 - VIS - VDD					85°C		520	
					125°C		550	
					–55°C		200	
					-40°C		210	
		0 V	0	15 V	25°C	125	240	
					85°C		300	
					125°C		300	
Change in ON Resistance		0 V	0 V	5 V		15		
(Between Any Two Channels),		0 V	0 V	10 V	25°C	10		Ω
ΔR _{ON}		0 V	0 V	15 V		5		



6.5 Electrical Characteristics (continued)

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5 \text{ V}$, and $R_L = 100 \Omega$, (unless otherwise noted)⁽¹⁾

	PARAMETER		TE	ST COND	ITIONS		MIN TYP	MAX	UNIT	
							–55°C		± 100	
OFF Channel Leakage Current: Any Channel OFF (Max)				0 V 18 V	–40°C					
			0 V		25°C	0.3	± 100 ⁽²⁾	nA		
or ALL Channels OFF (COMMON OUT/IN) (Max)					85°C		± 1000 (2)	11/4		
							125°C			
ON Channel Leakage Current: Any Channel ON (Max) or ALL Channels ON (COMMON OUT/IN) (Max)		t: Any	5 or 0	–5 V	0 V	10.5 V	85°C		± 800	
		5	0 V	0 V	18 V	85°C		± 800	nA	
	Input, C _{IS}							5		
	Output, C _{OS}	CD4051						30		
Capacitance	Output, C _{OS}	CD4052		0 V	0 V	10 V	25°C	18		pF
	Output, C _{OS}	CD4053						9		1
	Feed through,	C _{IOS}						0.2		
				R _L = 200	kΩ	5 V		30	60	
Prop Delay		V_{DD}	C _L = 50	οF	10 V	25°C	15	30	ns	
				$t_{r}, t_{f} = 20$	ns	15 V		10	20	



6.5 Electrical Characteristics (continued)

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5 \text{ V}$, and $R_1 = 100 \Omega$, (unless otherwise noted)(1)

	PARAMETER		TE	ST CONDI	TIONS		MIN TYP	MAX	UNIT
CONTROL (A	ADDRESS OR INHIBIT), V _C								
						–55°C	0.8		
						–40°C	0.8		
					5 V	25°C		0.8	
						85°C	0.8		
						125°C	0.8		
						–55°C	0.8		
						–40°C	0.8		
nput Low Vo	Itage, V _{IL} , Max				10 V	25°C		0.8	V
					85°C	0.8			
						125°C	0.8		
						–55°C	0.8		
						–40°C	0.8		
					15 V	25°C		0.8	
						85°C	0.8		
						125°C	0.8		
		-				–55°C	3.5		
						–40°C	3.5		
					5 V	25°C	3.5		
						85°C	3.5		
					125°C	3.5			
					−55°C	7			
						–40°C	7		
nput High Vo	oltage, V _{IH} , Min				10 V	25°C	7		V
						85°C	7		
						125°C	7		
						−55°C	11		
						–40°C	11		
					15 V	25°C	11		
						85°C	11		
						125°C	11		
						-55°C		±1	
						–40°C		±1	
nput current,	I _{IN} (Max)	V _{IN} = 0, 18			18 V	25°C	±0.6	±1	μΑ
	· ,					85°C		±1	•
						125°C		±1	
	Address-to-Signal OUT		0 V	0 V	5 V		450	720	
Dranagation (Channels ON	(Channels ON	t_{r} , $t_{f} = 20$ ns,	0 V	0 V	10 V		160	320	
Delay Time	or OFF) (See Figure 7-2, Figure 7-3,	$C_L = 50 \text{ pF},$ $R_L = 10 \text{ k}\Omega$	0 V	0 V	15 V		120	240	ns
-	and Figure 7-8)	10 K22	–5 V	0 V	5 V		225	450	
			0 V	0 V	5 V		400	720	
Propagation	Inhibit-to-Signal OUT	ee $\begin{aligned} t_r, & t_f = 20 \\ ns, & C_L = 50 \text{ pF}, \\ R_L = 1 \text{ k}\Omega & \end{aligned}$	0 V	0 V	10 V		160	320	
Delay Time	(Channel Turning ON) (See		0 V	0 V	15 V		120		ns
olay Timo	Figure 7-3)		-10 V	0 V	5 V		200		400



6.5 Electrical Characteristics (continued)

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5 \text{ V}$, and $R_L = 100 \Omega$, (unless otherwise noted)⁽¹⁾

	PARAMETER		TEST CONDITIONS							UNIT
		t _r , t _f = 20	0 V	0 V	5 V			200	450	
Propagation	Inhibit-to-Signal OUT (Channel Turning OFF)	ns,	0 V	0 V	10 V			90	210	no
Delay Time	(See Figure 7-10)	$C_L = 50 \text{ pF},$	0 V	0 V	15 V			70	160	60 ns
		$R_L = 10 \text{ k}\Omega$	–10 V	0 V	5 V			130	300	
Input Capacita	ance, C _{IN} (Any Address or Inh	ibit Input)	–5 V	0 V	5 V	25°C		5	7.5	pF

- Peak-to-Peak voltage symmetrical about (V_{DD} V_{EE}) / 2.
 Determined by minimum feasible leakage measurement for automatic testing.

6.6 AC Performance Characteristics

 $V_{DD} = +15 \text{ V}, V_{SS} = V_{EE} = 0 \text{ V},$

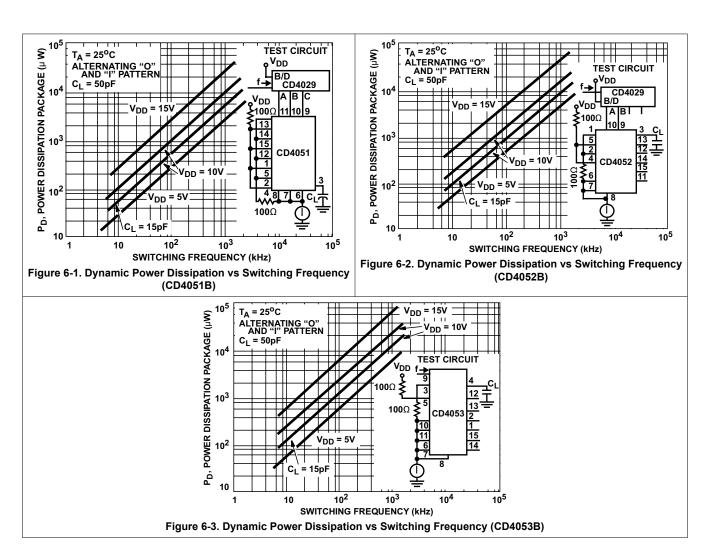
 $T_A = 25^{\circ}C$ (unless otherwise noted)

PARAMETER			TEST	CONDITIONS		TYP	UNIT
	V _{IS} (V)	V _{DD} (V)	R _L (kΩ)				
		10	1		CD4053	30	
Cutoff (–3dB)	5 ⁽¹⁾	10	1	V _{OS} at Common OUT/IN	CD4052	25	
Frequency Channel ON (Sine Wave		10	1		CD4051	20	MHz
Input)	V _{EE} = V _{SS} , 20Log(V _{OS} /V	_{IS}) = –3 dB		V _{OS} at Any Channel		60	
	2 ⁽¹⁾	5	10			0.3%	
Total Harmonic	3 ⁽¹⁾	10	10			0.2%	%
Distortion, THD	5 ⁽¹⁾	0.12%	70				
	V _{EE} = V _{SS} , f _{IS}	= 1 kHz Sine	Wave				
-40dB Feedthrough Frequency (All Channels OFF)	5 ⁽¹⁾	10	1	V _{OS} at Common OUT/IN	CD4053	8	
		1		Vos at Common CO 1/11	CD4052	10	MHz
	$V_{EE} = V_{SS}$, 20Log(V_{OS}/V) = _40 dB			CD4051	12	
	20209(105/1	IS)40 GD		V _{OS} at Any Channel		8	
	5 ⁽¹⁾	10	1			3	
				Data and Continue	Measured on Common	6	
–40dB Signal Crosstalk Frequency	$V_{EE} = V_{SS}$, $20Log(V_{OS}/V)$	_ 2 dD		Between Sections, CD4052 Only	Measured on Any Channel	10	MHz
riequency	20Log(V _{OS} /V	_{IS}) = -3 dB		Between Any Two	In Pin 2, Out Pin 14	2.5	
				Sections, CD4053 Only	In Pin 15, Out Pin 14	6	
Address-or-Inhibit-to-		10	10 ⁽²⁾		•	65	${\sf mV_{\sf PEAK}}$
Signal Crosstalk	$V_{EE} = 0, V_{SS}$ $V_{CC} = V_{DD} -$		ns, mVPEAK Wave)			65	${\rm mV_{PEAK}}$

- (1) Peak-to-Peak voltage symmetrical about $(V_{DD} V_{EE}) / 2$.
- (2) Both ends of channel.



6.7 Typical Characteristics



7 Parameter Measurement Information

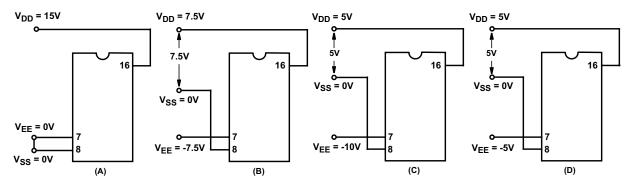


Figure 7-1. Typical Bias Voltages



Note

The ADDRESS (digital-control inputs) and INHIBIT logic levels are: $0 = V_{SS}$ and $1 = V_{DD}$. The analog signal (through the TG) may swing from V_{EE} to V_{DD} .

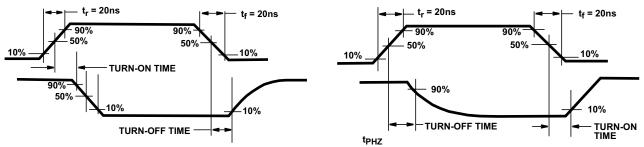


Figure 7-2. Waveforms, Channel Being Turned ON Figure 7-3. Waveforms, Channel Being Turned OFF (R_L = 1 k Ω) (R_L = 1 k Ω)

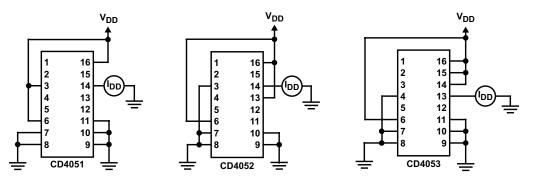


Figure 7-4. OFF Channel Leakage Current - Any Channel OFF

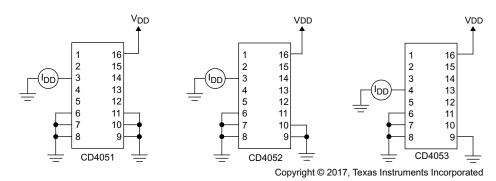


Figure 7-5. On Channel Leakage Current - Any Channel On

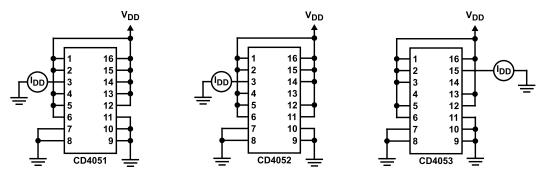


Figure 7-6. OFF Channel Leakage Current - All Channels OFF

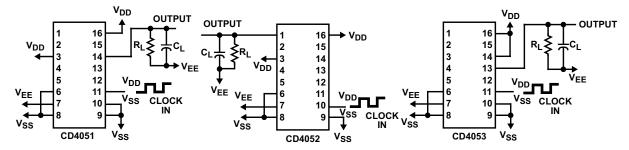


Figure 7-7. Propagation Delay – Address Input to Signal Output

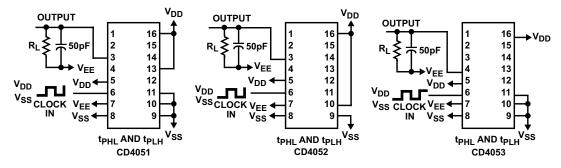


Figure 7-8. Propagation Delay – Inhibit Input to Signal Output

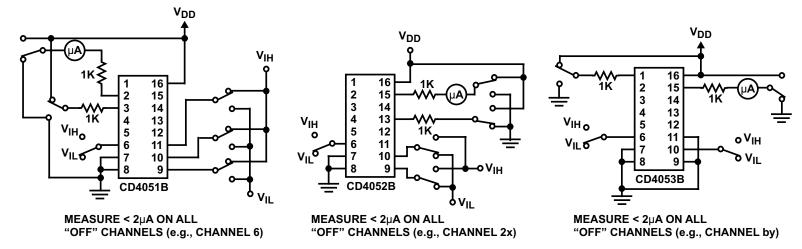


Figure 7-9. Input Voltage Test Circuits (Noise Immunity)

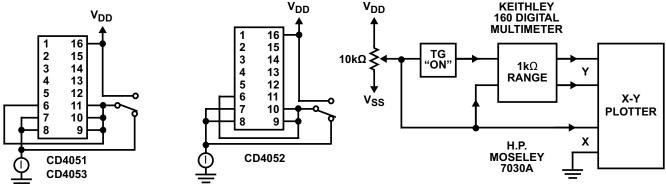


Figure 7-10. Quiescent Device Current

Figure 7-11. Channel ON Resistance Measurement Circuit



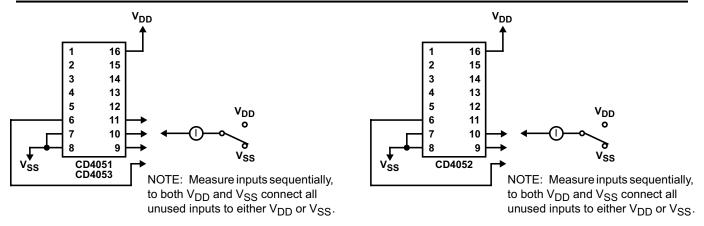


Figure 7-12. Input Current

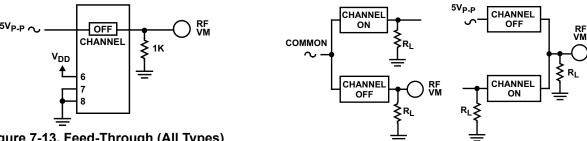
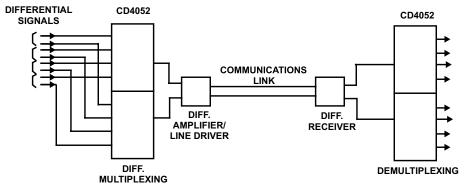


Figure 7-13. Feed-Through (All Types)

Figure 7-14. Crosstalk Between Any Two Channels (All Types)



Figure 7-15. Crosstalk Between Duals or Triplets (CD4052B, CD4053B)



 $\textbf{Special Considerations:} \ \text{In applications where separate power sources are used to drive } \ V_{DD} \ \text{and the signal inputs, the } \ V_{DD} \ \text{current}$ capability should exceed V_{DD}/R_L (R_L = effective external load). This provision avoids permanent current flow or clamp action on the V_{DD} supply when power is applied or removed from the CD4051B, CD4052B or CD4053B.

Figure 7-16. Typical Time-Division Application of the CD4052B



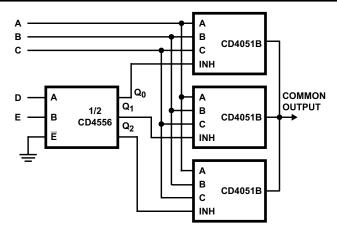


Figure 7-17. 24-to-1 MUX Addressing

8 Detailed Description

8.1 Overview

The CD4051B, CD4052B, and CD4053B analog multiplexers are digitally-controlled analog switches having low ON impedance and very low OFF leakage current. Control of analog signals up to 20 V_{P-P} can be achieved by digital signal amplitudes of 4.5 V to 20 V (if $V_{DD}-V_{SS}=3$ V, a $V_{DD}-V_{EE}$ of up to 13 V can be controlled; for $V_{DD}-V_{EE}$ level differences above 13 V, a $V_{DD}-V_{SS}$ of at least 4.5 V is required). For example, if $V_{DD}=+4.5$ V, $V_{SS}=0$ V, and $V_{EE}=-13.5$ V, analog signals from -13.5 V to +4.5 V can be controlled by digital inputs of 0 V to 5 V. These multiplexer circuits dissipate extremely low quiescent power over the full $V_{DD}-V_{SS}$ and $V_{DD}-V_{EE}$ supply-voltage ranges, independent of the logic state of the control signals. When a logic 1 is present at the inhibit input terminal, all channels are off.

The CD4051B device is a single 8-channel multiplexer having three binary control inputs, A, B, and C, and an inhibit input. The three binary signals select 1 of 8 channels to be turned on, and connect one of the 8 inputs to the output.

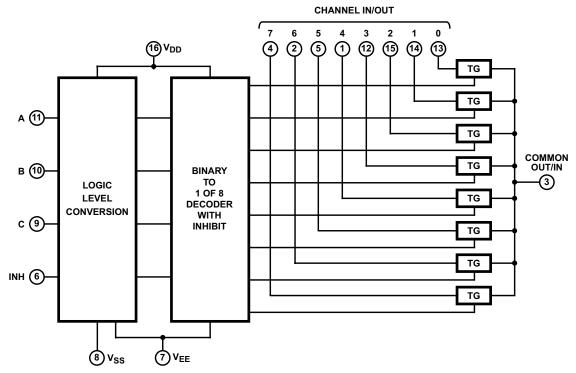
The CD4052B device is a differential 4-channel multiplexer having two binary control inputs, A and B, and an inhibit input. The two binary input signals select 1 of 4 pairs of channels to be turned on and connect the analog inputs to the outputs.

The CD4053B device is a triple 2-channel multiplexer having three separate digital control inputs, A, B, and C, and an inhibit input. Each control input selects one of a pair of channels which are connected in a single-pole, double-throw configuration.

When these devices are used as demultiplexers, the CHANNEL IN/OUT terminals are the outputs and the COMMON OUT/IN terminals are the inputs.

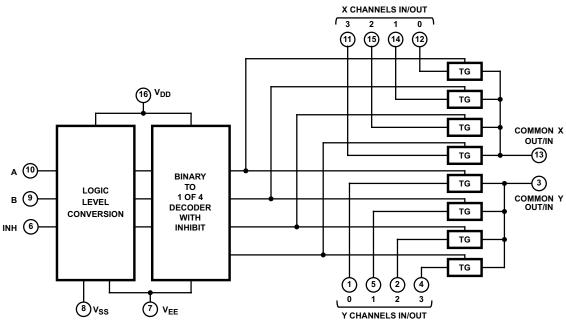


8.2 Functional Block Diagrams



All inputs are protected by standard CMOS protection network.

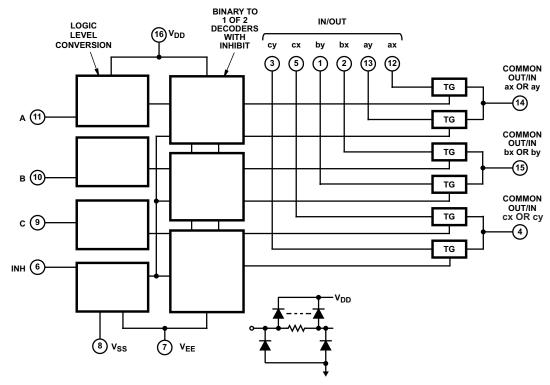
Figure 8-1. Functional Block Diagram, CD4051B



All inputs are protected by standard CMOS protection network.

Figure 8-2. Functional Block Diagram, CD4052B





All inputs are protected by standard CMOS protection network.

Figure 8-3. Functional Block Diagram, CD4053B

8.3 Feature Description

The CD405xB line of multiplexers and demultiplexers can accept a wide range of digital and analog signal levels. Digital signals range from 3 V to 20 V, and analog signals are accepted at levels \leq 20 V. The devices have low ON resistance, typically 125 Ω over 15 V_{P-P} signal input range for V_{DD} – V_{EE} = 18 V. This feature allows for very little signal loss through the switch. Matched switch characteristics are typically r_{ON} = 5 Ω for V_{DD} – V_{EE} = 15 V.

The CD405xB devices also have high OFF resistance, which keeps from wasting power when the switch is in the OFF position, with typical channel leakage of ± 100 pA at $V_{DD}-V_{EE}=18$ V. Very low quiescent power dissipation under all digital-control input and supply conditions, typically 0.2 μ W at $V_{DD}-V_{SS}=V_{DD}-V_{EE}=10$ V keeps power consumption total very low. All devices have been 100% tested for quiescent current at 20 V with maximum input current of 1 μ A at 18 V over the full package temperature range, and only 100 nA at 18 V and 25°C.

Logic-level conversion for digital addressing signals of 3 V to 20 V ($V_{DD} - V_{SS} = 3$ V to 20 V) to switch analog signals to 20 V_{P-P} ($V_{DD} - V_{EE} = 20$ V). Binary address decoding on chip makes channel selection easy. When channels are changed, a break-before-make system eliminates channel overlap.



8.4 Device Functional Modes

Table 8-1. Truth Table⁽¹⁾

	II	IPUT STATES		ON CHANNEL (C)
INHIBIT	С	В	Α	ON CHANNEL(S)
CD4051B				
0	0	0	0	0
0	0	0	1	1
0	0	1	0	2
0	0	1	1	3
0	1	0	0	4
0	1	0	1	5
0	1	1	0	6
0	1	1	1	7
1	X	X	Х	None
CD4052B				
0		0	0	0x, 0y
0		0	1	1x, 1y
0		1	0	2x, 2y
0		1	1	3x, 3y
1		X	X	None
CD4053B				
0	X	X	0	ax
0	Х	X	1	ay
0	X	0	X	bx
0	X	1	X	by
0	0	X	X	сх
0	1	X	X	су
1	X	X	X	None

⁽¹⁾ X = Do not care

9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The CD405xB multiplexers and demultiplexers can be used for a wide variety of applications.

9.2 Typical Application

One application of the CD4051B is to use it in conjunction with a microcontroller to poll a keypad. Figure 9-1 shows the basic schematic for such a polling system. The microcontroller uses the channel select pins to cycle through the different channels while reading the input to see if a user is pressing any of the keys. This application is a very robust setup, allowing for multiple simultaneous key-presses with very little power consumption. This setup also uses very few pins on the microcontroller. The down side of polling is that the microcontroller must continually scan the keys for a press and can do little else during this process.

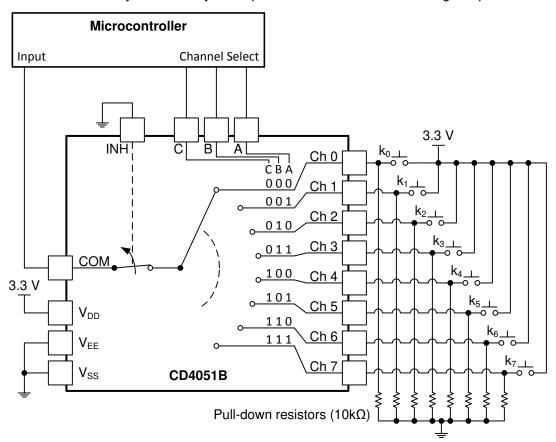


Figure 9-1. The CD4051B Being Used to Help Read Button Presses on a Keypad

9.2.1 Design Requirements

These devices use CMOS technology and have balanced output drive. Take care to avoid bus contention because it can drive currents that would exceed maximum limits. The high drive will also create fast edges into light loads, so routing and load conditions should be considered to prevent ringing.

9.2.2 Detailed Design Procedure

- 1. Recommended Input Conditions:
 - For switch time specifications, see propagation delay times in *Electrical Characteristics*.
 - Inputs should not be pushed more than 0.5 V above V_{DD} or below V_{EE}.
 - For input voltage level specifications for control inputs, see V_{IH} and V_{IL} in Electrical Characteristics.
- 2. Recommended Output Conditions:
 - Outputs should not be pulled above V_{DD} or below V_{EE}.
- 3. Input or output current consideration:
 - The CD405xB series of parts do not have internal current drive circuitry and thus cannot sink or source current. Any current will be passed through the device.

9.2.3 Application Curve

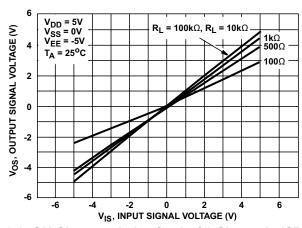


Figure 9-2. ON Characteristics for 1 of 8 Channels (CD4051B)

9.3 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Electrical Characteristics*.

Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, a 0.1- μ F bypass capacitor is recommended. If there are multiple pins labeled V_{CC} , then a 0.01- μ F or 0.022- μ F capacitor is recommended for each V_{CC} because the V_{CC} pins will be tied together internally. For devices with dual supply pins operating at different voltages, for example V_{CC} and V_{DD} , a 0.1- μ F bypass capacitor is recommended for each supply pin. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

9.4 Layout

9.4.1 Layout Guidelines

Reflections and matching are closely related to loop antenna theory, but different enough to warrant their own discussion. When a PCB trace turns a corner at a 90° angle, a reflection can occur. This reflection is primarily due to the change of width of the trace. At the apex of the turn, the trace width is increased to 1.414 times its width. This upsets the transmission line characteristics, especially the distributed capacitance and self–inductance of the trace — resulting in the reflection. It is a given that not all PCB traces can be straight, and so they will have to turn corners. Figure 9-3 shows progressively better techniques of rounding corners. Only the last example maintains constant trace width and minimizes reflections.



9.4.2 Layout Example

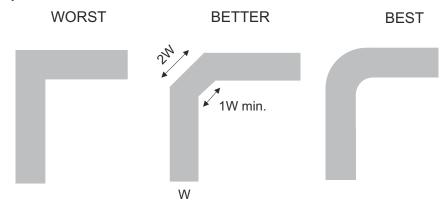


Figure 9-3. Trace Example



10 Device and Documentation Support

10.1 Documentation Support

10.1.1 Related Documentation

For related documentation, see the following:

Texas Instruments, Implications of Slow or Floating CMOS Inputs

10.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

10.4 Trademarks

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All trademarks are the property of their respective owners.

10.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
7901502EA	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	7901502EA CD4052BF3A	Samples
8101801EA	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	8101801EA CD4053BF3A	Samples
CD4051BE	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD4051BE	Samples
CD4051BEE4	OBSOLETE	PDIP	N	16		TBD	Call TI	Call TI	-55 to 125	CD4051BE	
CD4051BF	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD4051BF	Samples
CD4051BF3A	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD4051BF3A	Samples
CD4051BM	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4051BM	
CD4051BM96	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4051BM	Samples
CD4051BM96G3	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4051BM	
CD4051BM96G4	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4051BM	
CD4051BMT	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4051BM	
CD4051BNSR	ACTIVE	SO	NS	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4051B	Samples
CD4051BPW	OBSOLETE	TSSOP	PW	16		TBD	Call TI	Call TI	-55 to 125	CM051B	
CD4051BPWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM051B	Samples
CD4051BPWRG4	OBSOLETE	TSSOP	PW	16		TBD	Call TI	Call TI	-55 to 125	CM051B	
CD4052BE	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD4052BE	Samples
CD4052BEE4	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD4052BE	Samples
CD4052BF	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD4052BF	Samples
CD4052BF3A	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5 to 125 7901502EA CD4052BF3A	
CD4052BM	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4052BM	
CD4052BM96	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4052BM	Samples





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Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CD4052BM96G3	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4052BM	
CD4052BM96G4	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4052BM	
CD4052BMT	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4052BM	
CD4052BNSR	ACTIVE	SO	NS	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4052B	Samples
CD4052BPW	OBSOLETE	TSSOP	PW	16		TBD	Call TI	Call TI	-55 to 125	CM052B	
CD4052BPWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM052B	Samples
CD4052BPWRG3	OBSOLETE	TSSOP	PW	16		TBD	Call TI	Call TI	-55 to 125	CM052B	
CD4052BPWRG4	OBSOLETE	TSSOP	PW	16		TBD	Call TI	Call TI	-55 to 125	CM052B	
CD4053BE	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD4053BE	Samples
CD4053BEE4	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD4053BE	Samples
CD4053BF	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD4053BF	Samples
CD4053BF3A	ACTIVE	CDIP	J	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	8101801EA CD4053BF3A	Samples
CD4053BM	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4053M	
CD4053BM96	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4053M	Samples
CD4053BM96G3	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4053M	
CD4053BM96G4	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4053M	
CD4053BMT	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-55 to 125	CD4053M	
CD4053BNSR	ACTIVE	SO	NS	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4053B	Samples
CD4053BPW	OBSOLETE	TSSOP	PW	16		TBD	Call TI	Call TI	-55 to 125	CM053B	
CD4053BPWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM053B	Samples
CD4053BPWRG3	OBSOLETE	TSSOP	PW	16		TBD	Call TI	Call TI	-55 to 125	CM053B	
CD4053BPWRG4	OBSOLETE	TSSOP	PW	16		TBD	Call TI	Call TI	-55 to 125	CM053B	

⁽¹⁾ The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

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OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF CD4051B. CD4051B-MIL. CD4052B. CD4052B-MIL. CD4053B. CD4053B-MIL:

Catalog: CD4051B, CD4052B, CD4053B

Automotive: CD4051B-Q1, CD4051B-Q1, CD4053B-Q1, CD4053B-Q1

Military: CD4051B-MIL, CD4052B-MIL, CD4053B-MIL

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product



PACKAGE OPTION ADDENDUM

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- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Military QML certified for Military and Defense Applications



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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD4051BM96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD4051BM96G3	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1
CD4051BM96G4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD4051BNSR	so	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
CD4051BNSR	so	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
CD4051BPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD4052BM96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD4052BM96G3	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1
CD4052BM96G4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD4052BNSR	so	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
CD4052BNSR	so	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
CD4052BPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD4053BM96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD4053BM96G3	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1
CD4053BM96G4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD4053BNSR	SO	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1



PACKAGE MATERIALS INFORMATION

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Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD4053BNSR	so	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
CD4053BPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1



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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD4051BM96	SOIC	D	16	2500	356.0	356.0	35.0
CD4051BM96G3	SOIC	D	16	2500	364.0	364.0	27.0
CD4051BM96G4	SOIC	D	16	2500	340.5	336.1	32.0
CD4051BNSR	SO	NS	16	2000	356.0	356.0	35.0
CD4051BNSR	SO	NS	16	2000	353.0	353.0	32.0
CD4051BPWR	TSSOP	PW	16	2000	367.0	367.0	35.0
CD4052BM96	SOIC	D	16	2500	356.0	356.0	35.0
CD4052BM96G3	SOIC	D	16	2500	364.0	364.0	27.0
CD4052BM96G4	SOIC	D	16	2500	340.5	336.1	32.0
CD4052BNSR	SO	NS	16	2000	353.0	353.0	32.0
CD4052BNSR	SO	NS	16	2000	356.0	356.0	35.0
CD4052BPWR	TSSOP	PW	16	2000	367.0	367.0	35.0
CD4053BM96	SOIC	D	16	2500	356.0	356.0	35.0
CD4053BM96G3	SOIC	D	16	2500	364.0	364.0	27.0
CD4053BM96G4	SOIC	D	16	2500	340.5	336.1	32.0
CD4053BNSR	SO	NS	16	2000	353.0	353.0	32.0
CD4053BNSR	SO	NS	16	2000	356.0	356.0	35.0
CD4053BPWR	TSSOP	PW	16	2000	367.0	367.0	35.0



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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
Device	Fackage Name	rackage Type	FIIIS	3FQ	L (111111)	VV (111111)	ι (μιτι)	B (IIIII)
CD4051BE	N	PDIP	16	25	506	13.97	11230	4.32
CD4051BEE4	N	PDIP	16	25	506	13.97	11230	4.32
CD4051BEE4	N	PDIP	16	25	506	13.97	11230	4.32
CD4051BM	D	SOIC	16	40	506.6	8	3940	4.32
CD4051BM	D	SOIC	16	40	507	8	3940	4.32
CD4051BMG4	D	SOIC	16	40	506.6	8	3940	4.32
CD4051BMG4	D	SOIC	16	40	507	8	3940	4.32
CD4052BE	N	PDIP	16	25	506	13.97	11230	4.32
CD4052BEE4	N	PDIP	16	25	506	13.97	11230	4.32
CD4052BM	D	SOIC	16	40	507	8	3940	4.32
CD4052BMG4	D	SOIC	16	40	507	8	3940	4.32
CD4052BNS	NS	SOP	16	50	530	10.5	4000	4.1
CD4053BE	N	PDIP	16	25	506	13.97	11230	4.32
CD4053BEE4	N	PDIP	16	25	506	13.97	11230	4.32
CD4053BM	D	SOIC	16	40	507	8	3940	4.32
CD4053BMG4	D	SOIC	16	40	507	8	3940	4.32

14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.





SOP



- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing
- per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.



SOF



NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOF



NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.





SMALL OUTLINE PACKAGE



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



MECHANICAL DATA

NS (R-PDSO-G**)

14-PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



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